

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT				ATTY. DOCKET NO. 571-669		SERIAL NO. 09/678,395	
(Use several sheets if necessary)				APPLICANT Tanner et al.			
				FILING DATE October 3, 2000		GROUP 2881	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPLICABLE	
ve	4,746,794	May 24/88	John B. French et al.	250	288	Oct. 20/86	
ve	5,381,008	Jan. 10/95	Scott D. Tanner et al.	250	288	May 11/93	
ve	5,565,679	Oct. 15/96	Scott D. Tanner et al.	250	288	Nov. 04/94	
FOREIGN PATENT DOCUMENTS							
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
ve	WO98/56030	10/98	PCT/CA98/00536			YES NO	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
ve	D. J. Douglas, <i>Some Current Perspectives on ISP-MS</i> , Canadian Journal of Spectroscopy, Vol. 34, No. 2, 1989, pp. 38-49						
ve	John T. Rowan et al., <i>Attenuation of Polyatomic Ion Interferences in Inductively Coupled Plasma Mass Spectrometry by Gas-Phase Collisions</i> , Society for Applied Spectroscopy, Vol. 43, No. 6, 1989, pp. 976-980						
ve	I. B. Brenner, <i>Characterization of a New Collision Cell ICP-MS for Environmental and Geochemical Analysis</i> , 2000 Winter Conference on Plasma Spectrochemistry, Fort Lauderdale, FL., pp.338-339						
ve	Agilent Technologies Inc. Publication #5968-8813E, December 1999, pp. 1-12						
ve	Presentation #55 at FACSS, October 25, 1999 (abstract)						
ve	Takuyuki Nabeshima et al., <i>Development of Ion Trap Mass Spectrometer with Plasma Ion Source</i> , 2000 Winter Conference on Plasma Spectrochemistry, Fort Lauderdale, FL. (abstract)						
ve	Inductively Coupled Plasma Mass Spectrometry, ed. A. Montaser, 1998, p. 428						
EXAMINER: ZIA R. HASHMI				DATE CONSIDERED: 3/4/02			
EXAMINER: Initial if citation not considered, whether or not citation is in conformance with MPEP 609; draw Line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							